



[DOC] Reliability Of Semiconductor Lasers And Optoelectronic Devices (Woodhead Publishing Series In Electronic And Optical Materials)

Yeah, reviewing a ebook **Reliability of Semiconductor Lasers and Optoelectronic Devices (Woodhead Publishing Series in Electronic and Optical Materials)** could go to your near connections listings. This is just one of the solutions for you to be successful. As understood, success does not suggest that you have extraordinary points.

Comprehending as skillfully as treaty even more than extra will offer each success. neighboring to, the declaration as competently as acuteness of this Reliability of Semiconductor Lasers and Optoelectronic Devices (Woodhead Publishing Series in Electronic and Optical Materials) can be taken as skillfully as picked to act.

Reliability of Semiconductor Lasers and Optoelectronic Devices-Robert Herrick 2021-03-06 Reliability of Semiconductor Lasers and Optoelectronic Devices simplifies complex concepts of optoelectronics reliability with approachable introductory chapters and a focus on real-world applications. This book provides a brief look at the fundamentals of laser diodes, introduces reliability qualification, and then presents real-world case studies discussing the principles of reliability and what occurs when these rules are broken. Then this book comprehensively looks at optoelectronics devices and the defects that cause premature failure in them and how to control those defects. Key materials and devices are reviewed including silicon photonics, vertical-cavity surface-emitting lasers (VCSELs), InGaN LEDs and lasers, and AlGaN LEDs, covering the majority of optoelectronic devices that we use in our everyday lives, powering the Internet, telecommunication, solid-state lighting, illuminators, and many other applications. This book features contributions from experts in industry and academia working in these areas and includes numerous practical examples and case studies. This book is suitable for new entrants to the field of optoelectronics working in R&D. • Includes case studies and numerous examples showing best practices and common mistakes affecting optoelectronics reliability written by experts working in the industry • Features the first wide-ranging and comprehensive overview of fiber optics reliability engineering, covering all elements of the practice from building a reliability laboratory, qualifying new products, to improving reliability on mature products. • Provides a look at the reliability issues and failure mechanisms for silicon photonics, VCSELs, InGaN LEDs and lasers, AlGaN LEDs, and more.

Semiconductor Laser Engineering, Reliability and Diagnostics-Peter W. Epperlein 2013-03-18 This reference book provides a fully integrated novel approach to the development of high-power, single-transverse mode, edge-emitting diode lasers by addressing the complementary topics of device engineering, reliability engineering and device diagnostics in the same book, and thus closes the gap in the current book literature. Diode laser fundamentals are discussed, followed by an elaborate discussion of problem-oriented design guidelines and techniques, and by a systematic treatment of the origins of laser degradation and a thorough exploration of the engineering means to enhance the optical strength of the laser. Stability criteria of critical laser characteristics and key laser robustness factors are discussed along with clear design considerations in the context of reliability engineering approaches and models, and typical programs for reliability tests and laser product qualifications. Novel, advanced diagnostic methods are reviewed to discuss, for the first time in detail in book literature, performance- and reliability-impacting factors such as temperature, stress and material instabilities. Further key features include: practical design guidelines that consider also reliability related effects, key laser robustness factors, basic laser fabrication and packaging issues; detailed discussion of diagnostic investigations of diode lasers, the fundamentals of the applied approaches and techniques, many of them pioneered by the author to be fit-for-purpose and novel in the application; systematic insight into laser degradation modes such as catastrophic optical damage, and a wide range of technologies to increase the optical strength of diode lasers; coverage of basic concepts and techniques of laser reliability engineering with details on a standard commercial high power laser reliability test program. Semiconductor Laser Engineering, Reliability and Diagnostics reflects the extensive expertise of the author in the diode laser field both as a top scientific researcher as well as a key developer of high-power highly reliable devices. With invaluable practical advice, this new reference book is suited to practising researchers in diode laser technologies, and to postgraduate engineering students. Dr. Peter W. Epperlein is Technology Consultant with his own semiconductor technology consulting business Pwe-PhotonicsElectronics-IssueResolution in the UK. He looks back at a thirty years career in cutting edge photonics and electronics industries with focus on emerging technologies, both in global and start-up companies, including IBM, Hewlett-Packard, Agilent Technologies, Philips/NXP, Essient Photonics and IBM/JDSU Laser Enterprise. He holds Pre-Dipl. (B.Sc.), Dipl. Phys. (M.Sc.) and Dr. rer. nat. (Ph.D.) degrees in physics, magna cum laude, from the University of Stuttgart, Germany. Dr. Epperlein is an internationally recognized expert in compound semiconductor and diode laser technologies. He has accomplished R&D in many device areas such as semiconductor lasers, LEDs, optical modulators, quantum well devices, resonant tunneling devices, FETs, and superconducting tunnel junctions and integrated circuits. His pioneering work on sophisticated diagnostic research has led to many world's first reports and has been adopted by other researchers in academia and industry. He authored more than seventy peer-reviewed journal papers, published more than ten invention disclosures in the IBM Technical Disclosure Bulletin, has served as reviewer of numerous proposals for publication in technical journals, and has won five IBM Research Division Awards. His key achievements include the design and fabrication of high-power, highly reliable, single mode diode lasers. Book Reviews "Semiconductor Laser Engineering, Reliability and Diagnostics: A Practical Approach to High Power and Single Mode Devices". By Peter W. Epperlein Prof. em. Dr. Heinz Jäckel, High Speed Electronics and Photonics, Swiss Federal Institute of Technology ETH Zürich, Switzerland The book "Semiconductor Laser Engineering, Reliability and Diagnostics" by Dr. P.W. Epperlein is a landmark in the recent literature on semiconductor lasers because it fills a longstanding gap between many excellent books on laser theory and the complex and challenging endeavor to fabricate these devices reproducibly and reliably in an industrial, real world environment. Having worked myself in the early research and development of high power semiconductor lasers, I appreciate the competent, complete and skillful presentation of these three highly interrelated topics, where small effects have dramatic consequences on the success of a final product, on the ultimate performance and on the stringent reliability requirements, which are the name of the game. As the title suggests the author addresses three tightly interwoven and critical topics of state-of-the-art power laser research. The three parts are: device and mode stability engineering (chapter 1, 2), reliability mechanisms and reliability assessment strategies (chapter 3, 4, 5, 6) and finally material and device diagnostics (chapter 7, 8, 9) all treated with a strong focus on the implementation. This emphasis on the complex practical aspects for a large-scale power laser fabrication is a true highlight of the book. The subtle interplay between laser design, reliability strategies, advanced failure analysis and characterization techniques are elaborated in a very rigorous and scientific way using a very clear and easy to read representation of the complex interrelation of the three major topics. I will abstain from trying to provide a complete account of all the topics but mainly concentrate on the numerous highlights. The first part 1 "Laser Engineering" is divided in two chapters on basic electronic-optical, structural, material and resonator laser engineering on the one side, and on single mode control and stability at very high, still reliable power-levels with the trade-off between mirror damage, single mode stability on the other side. To round up the picture less well-known concepts and the state-of-the-art of large-area lasers, which can be forced into single-mode operation, are reviewed carefully. The subtle and complex interplay, which is challenging to optimize for a design for reliability and low stress as a major boundary condition is crucial for the design. The section gives a rather complete and well-referenced account of all relevant aspects, relations and trade-offs for understanding the rest of the book. The completeness of the presentation on power laser diode design based on basic physical and plausible arguments is mainly based on analytic mathematical relations as well as experiments providing a new and well-balanced addition for the power diode laser literature in particular. Modern 2D self-consistent electro-optical laser modeling including carrier hole burning and thermal effects – this is important because the weak optical guiding and gain-discrimination depend critically on rather small quantities and effects, which are difficult to optimize experimentally – is used in the book for simulation results, but is not treated separately. The novel and really original, "gap-filling" bulk of the book is elaborated by the author in a very clear way in the following four chapters in the part 2 "Laser Reliability" on laser degradation physics and mirror design and passivation at high power, followed then by two very application oriented chapters on reliability design engineering and practical reliability strategies and implementation procedures. This original combination of integral design and reliability aspects – which are mostly neglected in standard literature – is certainly a major plus of this book. I liked this second section as a whole, because it provides excellent insights in degradation physics on a high level and combines it in an interesting and skillful way with the less "glamorous" (unfortunately) but highly relevant reliability science and testing strategies, which is particularly important for devices operating at extreme optical stresses with challenging lifetime requirements in a real world environment. Finally, the last part 3 "Laser Diagnostics" comprising three chapters, is devoted mainly to advanced experimental diagnostics techniques for material integrity, mechanical stress, deep level defects, various dynamic laser degradation effects, surface- and interface quality, and most importantly heating and disordering of mirrors and mirror coatings. The topics of characterization techniques comprising micro-Raman- and micro-thermoreflectance-probing, 2K photoluminescence spectroscopy, micro-electroluminescence and photoluminescence scanning, and deep-level-transient spectroscopy have been pioneered by the author for the specific applications over many years guaranteeing many competent and well represented insights. These techniques are brilliantly discussed and the information distributed in many articles by the author has been successfully unified in a book form. In my personal judgment and liking, I consider the parts 2 and 3 on reliability and diagnostics as the most valuable and true novel contribution of the book, which in combination with the extremely well-covered laser design of part 1 clearly fill the gap in the current diode laser literature, which in this detail has certainly been neglected in the past. In summary, I can highly recommend this excellent, well-organized and clearly written book to readers who are already familiar with basic diode laser theory and who are active in the academic and industrial fabrication and characterization of semiconductor lasers. Due to its completeness, it also serves as an excellent reference of the current state-of-the-art in reliability engineering and device and material diagnostics. Needless to mention that the quality of the book, its representations and methodical structure meet the highest expectation and are certainly a tribute from the long and broad experience of the author in academic laser science and the industrial commercialization of high power diode lasers. In my opinion, this book was a pleasure to read and due to its quality and relevance deserves a large audience in the power diode laser community! Prof. em. Dr. Heinz Jäckel, High Speed Electronics and Photonics, Swiss Federal Institute of Technology ETH Zürich, Switzerland June 16, 2013 ===== "Semiconductor Laser Engineering, Reliability and Diagnostics: A Practical Approach to High Power and Single Mode Devices". By Peter W. Epperlein Dr. Chung-en Zah, Research Director, Semiconductor Technologies Research, S&T Division, Corning Incorporate, Corning NY, USA This book covers for the first time the three closely interrelated key laser areas of engineering (design), reliability and diagnostics in one book, written by the well-known practitioner in cutting-edge optoelectronics industries, Dr. Peter W. Epperlein. The book closes the gap in the current book literature and is thus a unique and excellent example of how to merge design, reliability and diagnostics aspects in a very professional, profound and complete manner. All physical and technological principles, concepts and practical aspects required for developing and fabricating highly-reliable high-power single-mode laser products are precisely specified and skillfully formulated along with all the necessary equations, figures, tables and worked-out examples making it easy to follow through the nine chapters. Hence, this unique book is a milestone in the diode laser literature and is an excellent reference book not only for diode laser researchers and engineers, but also diode laser users. The engineering part starts with a very informative and clear, well-presented account of all necessary basic diode laser types, principles, parameters and characteristics for an easy and quick understanding of laser functionality within the context of the book. Along with an elaborate and broad discussion of relevant laser material systems, applications, typical output powers, power-limiting factors and reliability tradeoffs, basic fabrication and packaging technologies, this excellent introductory section is well suited to become quickly and easily familiar with practical aspects and issues of diode laser technologies. Of special importance and high usefulness is the first analytic and quantitative discussion in a book on issues of coupling laser power into optical single mode fibers. The second section discusses in a well-balanced, competent and skillful way waveguide topics such as basic high-power design approaches, transverse vertical and lateral waveguide concepts, stability of the fundamental transverse lateral mode and fundamental mode waveguide optimization techniques by considering detrimental effects such as heating, carrier injection, spatial hole burning, lateral current spreading and gain profile variations. Less well-known approaches to force large-area lasers into a single mode operation are well-identified and carefully discussed in depth and breadth. All these topics are elaborated in a very complete, rigorous and scientific way and are clearly articulated and easy to read. In particular, the book works out the complex interaction between the many different effects to optimize high power single-mode performance at ultimate reliability and thus is of great benefit to every researcher and engineer engaged in this diode laser field. Another novelty and highlight is, for the first time ever in book form, a comprehensive yet concise discussion of diode laser reliability related issues. These are elaborated in four distinct chapters comprising laser degradation physics and modes, optical strength enhancement approaches including mirror passivation/coating and non-absorbing mirror technologies, followed by two highly relevant product-oriented chapters on reliability design engineering concepts and techniques and an elaborate reliability test plan for laser chip and module product qualification. This original and novel approach to link laser design to reliability aspects and requirements provides both, most useful insight into degradation processes such as catastrophic optical mirror damage on a microscopic scale, and a wide selection of effective remedial actions. These accounts, which are of highest significance for lasers operating at the optical stress limit due to extremely high output power densities and most demanding lifetime requirements are very professionally prepared and discussed in an interesting, coherent and skilful manner. The diagnostics part, consisting of three very elaborate chapters, is most unique and novel with respect to other diode laser books. It discusses for the first time ever on a very high level and in a competent way studies on material integrity, impurity trapping effects, mirror and cavity temperatures, surface- and interface quality, mirror facet disorder effects, mechanical stress and facet coating instability, and diverse laser temperature effects, dynamic laser degradation effects and mirror temperature maps. Of highest significance to design, performance and reliability are the various correlations established between laser device and material parameters. The most different and sophisticated experiments, carried out by the author at micrometer spatial resolutions and at temperatures as low as 2K, provide highly valuable insights into laser and material quality parameters, and reveal for the first time the origins of high power limitations on an atomic scale due to local heating effects and deep level defects. It is of great benefit, that the experimental techniques such as Raman spectroscopy, various luminescence techniques, thermoreflectance and deep-level transient spectroscopy, pioneered by the author for the specific experiments on lasers, are discussed with great expertise in depth and breadth, and the numerous paper articles published by the author are now represented in this book. The book has an elaborate table of contents and index, which are very useful, over 200 illustrative figures and tables, and extensive lists of references to all technical topics at the end of each of the nine chapters, which make it easy to follow from cover to cover or by jumping in at random areas of special interest. Moreover, experimental and theoretical concepts are always illustrated by practical examples and data. I can highly recommend this extremely relevant, well-structured and well-formulated book to all practising researchers in industrial and academic diode laser R&D environments and to post-graduate engineering students interested in the actual problems of designing, manufacturing, testing, characterising and qualifying diode lasers. Due to its completeness and novel approach to combine design, reliability and diagnostics in the same book, it can serve as an ideal reference book as well, and it deserves to be welcomed worldwide by the addressed audience. Dr. Chung-en Zah, Research Director, Semiconductor Technologies Research, S&T Division, Corning Incorporate, Corning NY, USA ===== "Semiconductor Laser Engineering, Reliability and Diagnostics: A Practical Approach to High Power and Single Mode Devices". By Peter W. Epperlein Robert W. Herrick, Ph.D., Senior Component Reliability Engineer, Intel Corp., Santa Clara, California, USA Dr. Epperlein has done the semiconductor laser community a great service, by releasing the most complete book on the market on the practical issues of how to make reliable semiconductor lasers. While dozens of books have been written over the past couple of decades on semiconductor laser design, only a handful have been written on semiconductor laser reliability. Prior to the release of this book, perhaps 40% of the material could be obtained elsewhere by combining five books: one on laser design, one on laser reliability, one on reliability calculations, and a couple of laser review books. Another 40% could be pieced together by collecting 50 -100 papers on the subjects of laser design, laser fabrication, characterization, and reliability. The remaining 20% have not previously been covered in any comprehensive way. Only the introductory material in the first half of the first chapter has good coverage elsewhere. The large majority of the knowledge in this book is generally held as "trade secret" by those with the expertise in the field, and most of those in the know are not free to discuss. The author was fortunate enough to work for the first half of his career in the IBM research labs, with access to unparalleled resources, and the ability to publish his work without trade secret restrictions. The results are still at the cutting edge of our understanding of semiconductor laser reliability today, and go well beyond the empirical "black box" approach many use of "try everything, and see what works." The author did a fine job of pulling together material from many disparate fields. Dr. Epperlein has particular expertise in high power single mode semiconductor lasers, and those working on those type of lasers will be especially interested in this book, as there has never been a book published on the fabrication and qualification of such lasers before. But those in almost any field of semiconductor lasers will learn items of interest about device design, fabrication, reliability, and characterization. Unlike most other books, which intend to convey the scientific findings or past work of the author, this one is written more as a "how to" manual, which should make it more accessible and useful to development engineers and researchers in the field. It also has over 200 figures, which make it easier to follow. As with many books of this type, it is not necessary to read it from cover-to-cover; it is best skimmed, with deep diving into any areas of special interest to the reader. The book is remarkable also for how comprehensive it is – even experts will discover something new and useful. Dr. Epperlein's book is an essential read for anyone looking to develop semiconductor lasers for anything other than pure research use, and I give it my highest recommendation. Robert W. Herrick, Ph.D., Senior Component Reliability Engineer, Intel Corp., Santa Clara, California, USA

Reliability and Degradation of Semiconductor Lasers and LEDs-Mitsuo Fukuda 1991-01-01 This comparative tutorial describes the reasons behind device failures and provides practical information on what can be done to minimize failure-

reliability-of-semiconductor-lasers-and-optoelectronic-devices-woodhead-publishing-series-in-electronic-and-optical-materials

prone designs and enhance device reliability. The text demonstrates how, with such advantages as smaller size, low-cost and simple operation, LEDs are well suited for a wide range of applications - especially in the field of optical fibre communication. This book should prove of interest to engineers and scientists in research, design, manufacturing and development of semiconductor lasers, LEDs and optical transmission systems.

Fabrication, Testing, and Reliability of Semiconductor Lasers- 1997

Testing, Packaging, Reliability and Applications of Semiconductor Lasers- 1999

RELIABILITY & DEGRADATION OF SEMICONDUCTOR LASERS.-M. FUKUDA 1991

Materials and Reliability Handbook for Semiconductor Optical and Electron Devices-Osamu Ueda 2012-09-22 Materials and Reliability Handbook for Semiconductor Optical and Electron Devices provides comprehensive coverage of reliability procedures and approaches for electron and photonic devices. These include lasers and high speed electronics used in cell phones, satellites, data transmission systems and displays. Lifetime predictions for compound semiconductor devices are notoriously inaccurate due to the absence of standard protocols. Manufacturers have relied on extrapolation back to room temperature of accelerated testing at elevated temperature. This technique fails for scaled, high current density devices. Device failure is driven by electric field or current mechanisms or low activation energy processes that are masked by other mechanisms at high temperature. The Handbook addresses reliability engineering for III-V devices, including materials and electrical characterization, reliability testing, and electronic characterization. These are used to develop new simulation technologies for device operation and reliability, which allow accurate prediction of reliability as well as the design specifically for improved reliability. The Handbook emphasizes physical mechanisms rather than an electrical definition of reliability. Accelerated aging is useful only if the failure mechanism is known. The Handbook also focuses on voltage and current acceleration stress mechanisms.

Advanced Laser Diode Reliability-Massimo Vanzi 2021-04-01 The book focuses on causes and effects of degradations of state-of-the-art semiconductor laser diodes. It aims to provide a tool for linking practical measurements to physical diagnostics. To this purpose, it reviews the current technologies, addressing their peculiar details that can promote specific failure mechanisms. Two sections will support this kernel: a) Failure Analysis techniques, procedures and examples; b) Device-oriented laser modelling and parameter extraction. • Talk about Natural continuity with the most widespread existing textbooks, published by Mitsuo Fukuda • Present the extension to new failure mechanisms, new technologies, new application fields, new environments • Introduce a specific self-consistent model for the physical description of a laser diode, expressed in terms of practically measurable quantities

Testing, Packaging, Reliability, and Applications of Semiconductor Lasers IV-Mahmoud Fallahi 1999

Packaging of High Power Semiconductor Lasers-Xingsheng Liu 2014-07-14 This book introduces high power semiconductor laser packaging design. The challenges of the design and various packaging and testing techniques are detailed by the authors. New technologies and current applications are described in detail.

Semiconductor Lasers and Diode-based Light Sources for Biophotonics-Peter E. Andersen 2018-10 Semiconductor lasers are small, reliable, low cost, high-performance and user-friendly optical devices which make them highly suitable for a variety of biomedical applications. This edited book gathers experts in the field to cover the fundamentals and technology advances of semiconductor lasers and diode-based lasers with a focus on their applications in medical optics and biophotonics including edge-emitting semiconductor lasers and light emitting diodes, Q-switched and mode-locked lasers, quantum cascade lasers, semiconductor disk lasers, near-infrared spectroscopy systems for biomedical applications, bio-medical Raman spectroscopy, nonlinear imaging and optical coherence tomography.

Optical Semiconductor Devices-Mitsuo Fukuda 1998-12-24 This book is devoted to optical semiconductor devices and their numerous applications in telecommunications, optoelectronics, and consumer electronics-areas where signal processing or the transmission of signals across fiber optic cables is paramount. It introduces a new generation of devices that includes optical modulators, quantum well (QW) lasers, and photodiodes and explores new applications of more established devices such as semiconductor lasers, light-emitting diodes, and photodiodes. Mitsuo Fukuda examines the material properties, operation principles, fabrication, packaging, reliability, and applications of each device and offers a unique industrial perspective, discussing everything engineers and scientists need to know at different phases of research, development, and production. This guide to the state-of-the-art of optical semiconductor devices: * Helps you choose the right device for a given application. * Covers important performance data such as temperature and optical feedback noise in lasers. * Highlights epitaxial growth techniques and fabrication for each device. * Features one hundred figures and an extensive bibliography. * Provides a clear and concise treatment, unencumbered by excessive theory Optical Semiconductor Devices is an essential resource for engineers and researchers in telecommunications and optoelectronics, equipment designers and manufacturers, and graduate students and scholars interested in this rapidly evolving field.

Physics of Semiconductor Lasers-B. Mroziewicz 2017-01-31 Written for readers who have some background in solid state physics but do not necessarily possess any knowledge of semiconductor lasers, this book provides a comprehensive and concise account of fundamental semiconductor laser physics, technology and properties. The principles of operation of these lasers are therefore discussed in detail with the interrelations between their design and optical, electrical and thermal properties. The relative merits of a large number of laser structures and their parameters are described to acquaint the reader with the various aspects of the semiconductor lasers and the trends in their development.

Reliability and Radiation Effects in Compound Semiconductors

Semiconductor Device Reliability-A. Christou 2012-12-06 This publication is a compilation of papers presented at the Semiconductor Device Reliability Workshop sponsored by the NATO International Scientific Exchange Program. The Workshop was held in Crete, Greece from June 4 to June 9, 1989. The objective of the Workshop was to review and to further explore advances in the field of semiconductor reliability through invited paper presentations and discussions. The technical emphasis was on quality assurance and reliability of optoelectronic and high speed semiconductor devices. The primary support for the meeting was provided by the Scientific Affairs Division of NATO. We are indebted to NATO for their support and to Dr. Craig Sinclair, who admin isters this program. The chapters of this book follow the format and order of the sessions of the meeting. Thirty-six papers were presented and discussed during the five-day Workshop. In addition, two panel sessions were held, with audience participation, where the particularly controversial topics of burn-in and reliability modeling and prediction methods were discussed. A brief review of these sessions is presented in this book.

Surface Emitting Semiconductor Lasers and Arrays-Gary A. Evans 1993 Reviews all the basic types of surface emitting semiconductor lasers, including vertical cavity, etched-mirror integrated beam deflectors and grating out-coupled devices. The book also addresses such topics as edge-emitting arrays, thermal management and coherence.

Introduction to Semiconductor Lasers for Optical Communications-David J. Klotzkin 2013-11-30 This textbook provides a thorough and accessible treatment of semiconductor lasers from a design and engineering perspective. It includes both the physics of devices as well as the engineering, designing and testing of practical lasers. The material is presented clearly with many examples provided. Readers of the book will come to understand the finer aspects of the theory, design, fabrication and test of these devices and have an excellent background for further study of optoelectronics. This book also: Provides a multi-faceted approach to explaining the theories behind semiconductor lasers, utilizing mathematical examples, illustrations and written theoretical presentations Offers a balance of relevant optoelectronic topics, with specific attention given to distributed feedback lasers, growth techniques and waveguide cavity design Provides a summary of every chapter, worked examples, and problems for readers to solve Incorporates and explains recent breakthroughs in laser design

Materials and Reliability Handbook for Semiconductor Optical and Electron Devices-Osamu Ueda 2012-09-24 Materials and Reliability Handbook for Semiconductor Optical and Electron Devices provides comprehensive coverage of reliability procedures and approaches for electron and photonic devices. These include lasers and high speed electronics used in cell phones, satellites, data transmission systems and displays. Lifetime predictions for compound semiconductor devices are notoriously inaccurate due to the absence of standard protocols. Manufacturers have relied on extrapolation back to room temperature of accelerated testing at elevated temperature. This technique fails for scaled, high current density devices. Device failure is driven by electric field or current mechanisms or low activation energy processes that are masked by other mechanisms at high temperature. The Handbook addresses reliability engineering for III-V devices, including materials and electrical characterization, reliability testing, and electronic characterization. These are used to develop new simulation technologies for device operation and reliability, which allow accurate prediction of reliability as well as the design specifically for improved reliability. The Handbook emphasizes physical mechanisms rather than an electrical definition of reliability. Accelerated aging is useful only if the failure mechanism is known. The Handbook also focuses on voltage and current acceleration stress mechanisms.

Semiconductor Lasers and Heterojunction LEDs-Henry Kressel 1977

Semiconductor Lasers-Govind P. Agrawal 2013-11-27 Since its invention in 1962, the semiconductor laser has come a long way. Advances in material purity and epitaxial growth techniques have led to a variety of semiconductor lasers covering a wide wavelength range of 0. 3- 100 –m. The development during the 1970s of GaAs semiconductor lasers, emitting in the near-infrared region of 0. 8-0. 9 –m, resulted in their use for the first generation of optical fiber communication systems. However, to take advantage oflow losses in silica fibers occurring around 1. 3 and 1. 55 –m, the emphasis soon shifted toward long-wavelength semiconductor lasers. The material system of choice in this wavelength range has been the quaternary alloy InGaAsP. During the last five years or so, the intense development effort devoted to InGaAsP lasers has resulted in a technology mature enough that lightweight transmission systems using InGaAsP lasers are currently being deployed throughout the world. This book is intended to provide a comprehensive account of long-wave length semiconductor lasers. Particular attention is paid to InGaAsP lasers, although we also consider semiconductor lasers operating at longer wave lengths. The objective is to provide an up-to-date understanding of semicon ductor lasers while incorporating recent research results that are not yet available in the book form. Although InGaAsP lasers are often used as an example, the basic concepts discussed in this text apply to all semiconductor lasers, irrespective of their wavelengths.

Testing, Packaging, and Reliability of Semiconductor Lasers V-Society of Photo-optical Instrumentation Engineers 2000

Semiconductor Lasers I-Eli Kapon 1999-01-12 This book covers the device physics of semiconductor lasers in five chapters written by recognized experts in this field. The volume begins by introducing the basic mechanisms of optical gain in semiconductors and the role of quantum confinement in modern quantum well diode lasers. Subsequent chapters treat the effects of built-in strain, one of the important recent advances in the technology of these lasers, and the physical mechanisms underlying the dynamics and high speed modulation of these devices. The book concludes with chapters addressing the control of photon states in squeezed-light and microcavity structures, and electron states in low dimensional quantum wire and quantum dot lasers. The book offers useful information for both readers unfamiliar with semiconductor lasers, through the introductory parts of each chapter, as well as a state-of-the-art discussion of some of the most advanced semiconductor laser structures, intended for readers engaged in research in this field. This book may also serve as an introduction for the companion volume, Semiconductor Lasers II: Materials and Structures, which presents further details on the different material systems and laser structures used for achieving specific diode laser performance features. Introduces the reader to the basics of semiconductor lasers Covers the fundamentals of lasing in semiconductors, including quantum confined and microcavity structures Beneficial to readers interested in the more general aspects of semiconductor physics and optoelectronic devices, such as quantum confined heterostructures and integrated optics Each chapter contains a thorough introduction to the topic geared toward the non-expert, followed by an in-depth discussion of current technology and future trends Useful for professionals engaged in research and development Contains numerous schematic and data-containing illustrations

Semiconductor Lasers and Laser Dynamics- 2004

Reliability Problems of Semiconductor Lasers-P. G. Eliseev 1991

Diode Lasers-D. Sands 2004-10-30 Diode lasers use nearly microscopic chips of gallium-arsenide or other exotic semiconductor material to generate coherent light in a very small package. Their compact size, reliability, and low cost means that they find applications in all aspects of modern technology-most importantly they drive modern optical telecommunication systems. Diod

Semiconductor Lasers-Alexei Baranov 2013-04-23 Semiconductor lasers have important applications in numerous fields, including engineering, biology, chemistry and medicine. They form the backbone of the optical telecommunications infrastructure supporting the internet, and are used in information storage devices, bar-code scanners, laser printers and many other everyday products. Semiconductor lasers: Fundamentals and applications is a comprehensive review of this vital technology. Part one introduces the fundamentals of semiconductor lasers, beginning with key principles before going on to discuss photonic crystal lasers, high power semiconductor lasers and laser beams, and the use of semiconductor lasers in ultrafast pulse generation. Part two then reviews applications of visible and near-infrared emitting lasers. Nonpolar and semipolar GaN-based lasers, advanced self-assembled InAs quantum dot lasers and vertical cavity surface emitting lasers are all considered, in addition to semiconductor disk and hybrid silicon lasers. Finally, applications of mid- and far-infrared emitting lasers are the focus of part three. Topics covered include GaSb-based type I quantum well diode lasers, interband cascade and terahertz quantum cascade lasers, whispering gallery mode lasers and tunable mid-infrared laser absorption spectroscopy. With its distinguished editors and international team of expert contributors, Semiconductor lasers is a valuable guide for all those involved in the design, operation and application of these important lasers, including laser and telecommunications engineers, scientists working in biology and chemistry, medical practitioners, and academics working in this field. Provides a comprehensive review of semiconductor lasers and their applications in engineering, biology, chemistry and medicine Discusses photonic crystal lasers, high power semiconductor lasers and laser beams, and the use of semiconductor lasers in ultrafast pulse generation Reviews applications of visible and near-infrared emitting lasers and mid- and far-infrared emitting lasers

High-speed Semiconductor Lasers for Communication-Society of Photo-optical Instrumentation Engineers 1997

Semiconductor Optoelectronic Device Manufacturing and Applications-David Chen 2001

Diode Lasers and Photonic Integrated Circuits-Larry A. Coldren 2012-03-02 Diode Lasers and Photonic Integrated Circuits, Second Edition provides a comprehensive treatment of optical communication technology, its principles and theory, treating students as well as experienced engineers to an in-depth exploration of this field. Diode lasers are still of significant importance in the areas of optical communication, storage, and sensing. Using the the same well received theoretical foundations of the first edition, the Second Edition now introduces timely updates in the technology and in focus of the book. After 15 years of development in the field, this book will offer brand new and updated material on GaN-based and quantum-dot lasers, photonic IC technology, detectors, modulators and SOAs, DVDs and storage, eye diagrams and BER concepts, and DFB lasers. Appendices will also be expanded to include quantum-dot issues and more on the relation between spontaneous emission and gain.

Semiconductors and Semimetals- 1985-03-28 Semiconductors and Semimetals

Reliability and Degradation-M. J. Howes 1981

Laser Optics of Condensed Matter-E. Garmire 2012-12-06 The Fourth USA-USSR Symposium. on The Physics of Optical Phenomena and Their Use as Probes of Matter, was held in Irvine, California, January 23-27, 1990. Participating in the Symposium were 22 scientists from the USSR and 29 from the USA. In addition, to provide an international dimension to this Symposium without, however, compromising significantly its essentially binational character, 7 non-US and non-USSR scientists were invited to take part in it. The present volume is the proceedings of that Symposium, and contains all manuscripts received prior to August 1, 1990, representing, scientific contributions presented. A few manuscripts were not received, but for completeness the corresponding abstract is printed.. Three previous USA/USSR Binational Symposia on related topics have been held, viz. "Theory of Light Scattering in Condensed Matter" (Moscow, 1975), "Light Scattering in

Solids" (New York, 1979), and "Laser Optics of Condensed Matter" (Leningrad, 1987). These meetings were evaluated by the participants as highly successful and provided invaluable oppor tunities for researchers to exchange information and to initiate colla borative work which led to research visits by US physicist to Soviet laboratories, and vice versa, and which continue to the present day.

High Power Laser Handbook-Hagop Injeyan 2011-01-05 The State of the Art in High-Power Laser Technology Filled with full-color images, High-Power Laser Handbook offers comprehensive details on the latest advances in high-power laser development and applications. Performance parameters for each major class of lasers are described. The book covers high-power gas, chemical, and free-electron lasers and then discusses semiconductor diode lasers, along with the associated technologies of packaging, reliability, and beam shaping and delivery. Current research and development in solid-state lasers is described as well as scaling approaches for high CW powers, high pulse energies, and high peak powers. This authoritative work also addresses the emergence of fiber lasers and concludes by reviewing various methods for beam combining. Coverage Includes: Carbon dioxide lasers Excimer lasers Chemical lasers High-power free-electron lasers Semiconductor laser diodes High-power diode laser arrays Introduction to high-power solid-state lasers Zig-zag slab lasers ThinZag high-power laser development Thin disk lasers Heat capacity lasers Ultrafast solid-state lasers Ultrafast lasers in the thin disk geometry The National Ignition Facility laser Optical fiber lasers Pulsed fiber lasers High-power ultrafast fiber laser systems High-power fiber lasers for industry and defense Beam combining

In-plane Semiconductor Lasers- 2000

Single Frequency Semiconductor Lasers-Jens Buus 1991 This tutorial text describes the properties of advanced semiconductor lasers in detail. Although the text gives a detailed theoretical account, a number of practical examples and experimental results are described as well. The material presented is at an advanced level and is of particular interest to scientists and engineers with a basic familiarity with semiconductor lasers who would like a description of the properties of single frequency semiconductor lasers and of the possibilities offered by these devices.

High-Power Diode Lasers-Roland Diehl 2003-07-01 Starting from the basics of semiconductor lasers with emphasis on the generation of high optical output power the reader is introduced in a tutorial way to all key technologies required to fabricate high-power diode-laser sources. Various applications are exemplified.

Semiconductor Lasers III-China Optics & Optoelectronic Manufacturers Association 1998

Long-Wavelength Semiconductor Lasers-Govind Agrawal 2012-06-12 Since its invention in 1962, the semiconductor laser has come a long way. Advances in material purity and epitaxial growth techniques have led to a variety of semiconductor lasers covering a wide wavelength range of 0. 3- 100 lLm. The development during the 1970s of GaAs semiconductor lasers, emitting in the near-infrared region of 0. 8--0. 9 lLm, resulted in their use for the first generation of optical fiber communication systems. However, to take advantage of low losses in silica fibers occurring around 1. 3 and 1. 55 lLm, the emphasis soon shifted toward long-wavelength semiconductor lasers. The material system of choice in this wavelength range has been the quaternary alloy InGaAsP. During the last five years or so, the intense development effort devoted to InGaAsP lasers has resulted in a technology mature enough that lightwave transmission systems using InGaAsP lasers are currently being deployed throughout the world. This book is intended to provide a comprehensive account of long-wave length semiconductor lasers. Particular attention is paid to InGaAsP lasers, although we also consider semiconductor lasers operating at longer wave lengths. The objective is to provide an up-to-date understanding of semicon ductor lasers while incorporating recent research results that are not yet available in the book form. Although InGaAsP lasers are often used as an example, the basic concepts discussed in this text apply to all semiconductor lasers, irrespective of their wavelengths.

Laser and Laser Systems Reliability-Society of Photo-optical Instrumentation Engineers 1982

The Principles of Semiconductor Laser Diodes and Amplifiers-